

# **PCT**

#### INTERNATIONAL SEARCH REPORT

(PCT Article 18 and Rules 43 and 44)

Applicant's or agent's file reference IR-3224C-PCT		Transmittal of International Search Report 0) as well as, where applicable, item 5 below.
International application No.	International filing date (day/month/year)	(Earliest) Priority Date (day/month/year)
PCT/US92/10873	21 DECEMBER 1992	26 DECEMBER 1991
Applicant ELF ATOCHEM NORTH AMERICA	, INC.	
•	en prepared by this International Searching Aung transmitted to the International Bureau.	thority and is transmitted to the applicant
This international search report consists	s of a total of $\frac{2}{}$ sheets.	
X It is also accompanied by a c	copy of each prior art document cited in this r	report.
1. Certain claims were found	unsearchable (Sec Box I).	•
2. Unity of invention is lacking	g (See Box II).	
	n contains disclosure of a nucleotide and/oried out on the basis of the sequence listing	r amino acid sequence listing and the
	filed with the international application.	
	furnished by the applicant separately from the	international application,
	1 1	ent to the effect that it did not include matter he international application as filed.
	transcribed by this Authority.	· · · · · · · · · · · · · · · · ·
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	the text is approved as submitted by the applic	
<u> </u>	the text has been established by this Authority	to read as follows:
5. With regard to the abstract,		
X	the text is approved as submitted by the applic	eant.
	the text has been established, according to Ru in Box III. The applicant may, within one international search report, submit comments	month from the date of mailing of this
6. The figure of the drawings to be p	ublished with the abstract is:	
	as suggested by the applicant.	Name of the Course
rigulo ito.		
	because the applicant failed to suggest a figure	None of the figures.

## INTERNATIONAL SEARCH REPORT

•			PCT/US92/108	73		
IPC(5) US CL	SSIFICATION OF SUBJECT MATTER :G01G 19/02; C07F 7/22 :106/287.16; 252/305; 106/287.24 to International Patent Classification (IPC) or to both	national classification	and IPC			
B. FIEI	LDS SEARCHED		· · · · · · · · · · · · · · · · · · ·			
Minimum d	locumentation searched (classification system followe	d by classification sym	ibols)			
U.S. :	106/287.16;252/305;106/28	7.24				
Documentat	tion searched other than minimum documentation to th	e extent that such docu	ments are included	in the fields searched		
Electronic d	data base consulted during the international search (na	ame of data base and,	where practicable	, search terms used)		
C. DOC	CUMENTS CONSIDERED TO BE RELEVANT		·			
Category*	Citation of document, with indication, where a	ppropriate, of the relev	vant passages	Relevant to claim No.		
Y	SU, A, 0833649 05 June 1981, See at	1-5,11-13, 16-26				
Y	JA, A, 58-189263 (HITACHI CHEMIC abstract.	6,14,15				
Y	JA, A, 57-34164 (KANSAI PAINT) 24	1-5,7,11-13, 15-26				
Y	See abstract,	1-5,7-13, 16-26				
Furth	ler documents are listed in the continuation of Box C	C. See paten	nt family annex.			
* Sp	ecial categories of cited documents:			ernational filing date or priority ation but cited to understand the		
	cument defining the general state of the art which is not considered be part of particular relevance		eory underlying the inv			
"E" car	rlier document published on or after the international filing date			e claimed invention cannot be red to involve an inventive step		
"L" document which may throw doubts on priority claim(s) or which is when the document is taken alone cited to establish the publication date of another citation or other						
"O" do	special reason (as specified)  *Y*  document of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document invention of particular relevance; the claimed invention cannot be considered to involve an inventive step when the document invention cannot be combined with one or more other such documents, such combination being obvious to a person skilled in the art					
	cument published prior to the international filing date but later than epriority date claimed	"&" document men	nber of the same patent	family		
	actual completion of the international search	Date of mailing of th	ne international sea	irch report		
11 FEBR	UARY 1993		) 5 MAR 19	93		
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Washington	n, D.C. 20231 No. NOT APPLICABLE		03) 308-0662			
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#### PATENT COOPERATION TREATY

# **PCT**

#### NOTIFICATION OF THE RECOR OF A CHANGE

	To:  HENN, Robert, B. Elf Atochem North America, Inc Patent Department, 26th Floor 2000 Market Street Philadelphia, PA 19103-3222 ETATS-UNIS D'AMERIQUE			
PCT  NOTIFICATION OF THE RECORDING OF A CHANGE  (PCT Rule 92bis.1 and Administrative Instructions, Section 422)  Date of mailing (day/month/year) 23 August 1993 (23.08.93)				
Applicant's or agent's file reference  IR-3224C-PCT  International application No.  PCT/US92/10873	IMPORTANT NOTIFICATION  International filing date (day/month/year) 21 December 1992 (21.12.92)			
1. The following indications appeared on record concerning: the applicant the inventor	X the agent	the comm	on representative	
Name and Address	<del></del>	State of Nationality	State of Residence	
HENN, Robert, B. Elf Atochem North America, Inc. Three Parkway		Telephone No.		
Philadelphia, PA 19102-1303 United States of America		Facsimile No.		
		Teleprinter No.	·	
2. The International Bureau hereby notifies the applicant that	the following chan	ge has been recorded co	ncerning:	

HENN, Robert, B.			
Elf Atochem North America, Inc.	Telephone No.		
Three Parkway Philadelphia, PA 19102-1303 United States of America	Facsimile No.		
	Teleprinter No.		
2. The International Bureau hereby notifies the applicant that the following change	has been recorded co	ncerning:	
		e residence	
Name and Address	State of Nationality	State of Residence	
HENN, Robert, B.			
Elf Atochem North America, Inc. Patent Department, 26th Floor	Telephone No. 215/419-77	792	
2000 Market Street	Facsimile No.	<i>J</i>	
Philadelphia, PA 19103-3222 United States of America			
onited states of America	Teleprinter No.		
3. Further observations, if necessary:			
4. A copy of this notification has been sent to:			
X the receiving Office X the designated	d Offices concerned		
the International Searching Authority	ffices concerned		
the International Preliminary Examining Authority other:			
	1. 1		

The International Bureau of WIPO 34, chemin des Colombettes 1211 Geneva 20, Switzerland

Authorized officer

Telephone No. (41-22) 730.91.11

Facsimile No. (41-22) 740.14.35

## **PCT**

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#### **REQUEST**

The undersigned requests that the present international application be processed according to the Patent Cooperation Treaty.

PCTIUS 9 2 / 1 0 8 7 3
International Application No.

International Filing Date

PCT INTERNATIONAL

Name of receiving Office and PCT International Application."

Applicant's or agent's file reference (if desired) (12 characters maximum) IR-3224C-PCT Box No. I TITLE OF INVENTION COATING COMPOSITION FOR GLASS Box No. 11 APPLICANT (Family name followed by given name; for a legal entity, full official designation. The address must include postal code and name of country.) Name and address: This person is also inventor. ELF ATOCHEM NORTH AMERICA, INC. Telephone No. Three Parkway (215) 587-7000 Philadelphia, Pennsylvania 19102-1303 United States of America Facsimile No. (215) 587-7075 Teleprinter No. State (i.e. country) of nationality: State (i.e. country) of residence: US US This person is applicant Tall designated all designated States except the United States the States indicated in for the purposes of: States the United States of America of America only the Supplemental Box Box No. III FURTHER APPLICANTS AND/OR (FURTHER) INVENTORS (Family name followed by given name; for a legal entity, full official designation. The address must include postal code and name of country.) Name and address: This person is: RUSSO, David A. applicant only 22 Brenda Lane Norristown, Pennsylvania 19403-2002 applicant and inventor United States of America inventor only (If this check-hox is marked, do not fill in below.) State (i.e. country) of nationality: State (i.e. country) of residence: This person is applicant all designated all designated States except the United States the States indicated in for the purposes of: the United States of America of America only the Supplemental Box (Family name followed by given name: for a legal entity, full official designation. The address must include postal code and name of country.) Name and address: This person is: applicant only DIRKX, Ryan R. 2006 Turnberry Circle applicant and inventor Glenmoore, Pennsylvania 19343 United States of America inventor only (If this check-box is marked, do not fill in below.) State (i.e. country) of nationality: State (i.e. country) of residence: This person is applicant all designated all designated States except the United States the States indicated in for the purposes of: States the United States of America of America only the Supplemental Box Further applicants and/or (further) inventors are indicated on a continuation sheet.

Continuation of Box No. III FURTHER APPLICANTS AND/OR (FURTHER) INVENTORS				
If none of the following sub-boxes is used, this sheet is a	not to be included in the request.			
Name and address: (Family name followed by given name; for a legal entity, fur designation. The address must include postal code and name of FLORCZAK, Glenn P.  2 Hilltop Boulevard East Brunswick, New Jersey 08816-2831 United States of America				
State (i.e. country) of nationality:  State (i.e. country)	unury) of residence:			
This person is applicant for the purposes of:  all designated all designated States except the United States of America	X the United States the States indicated in the Supplemental Box			
Name and address: (Family name followed by given name; for a legal entity, ful designation. The address must include postul code and name of	This person is:  applicant only  applicant and inventor  inventor only (If this check-box is marked, do not fill in below.)			
State (i.e. country) of nationality:  State (i.e. cou	nury) of residence:			
This person is applicant for the purposes of:  all designated all designated States except the United States of America	the United States the States indicated in the Supplemental Box			
Name and address: (Family name followed by given name: for a legal entity, ful designation. The address must include postal code and name of	This person is:  applicant only  applicant and inventor  inventor only (If this check-box is marked, do not fill in below.)			
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This person is applicant for the purposes of:  all designated all designated States except the United States of America	the United States the States indicated in the Supplemental Box			
Name and address: (Family name followed by given name; for a legal entity, full designation. The address must include postal code and name of c	This person is:  applicant only  applicant and inventor  inventor only (If this check-box is marked, do not fill in below.)			
State (i.e. country) of nationality:  State (i.e. country)	(ry) of residence:			
This person is applicant all designated all designated States except for the purposes of:  all designated States except the United States of America	the United States the States indicated in the Supplemental Box			
Further applicants and/or (further) inventors are indicated on another conti	nuation sheet.			

Sheet	No	3
	1	

ox No. IV	AGENT OR COMMON REPRESENTATIV	E: OR ADDRESS FO	R CORRESPONDENCE
<u> </u>			R CORRESPONDENCE
the appli	identified below is hereby/has been appointed to accant(s) before the competent International Authorit	ies as:	agent common representativ
ame and	address: (Family name followed by given name: for designation. The address must include postal	r a legal entity, full official code and name of country.	<b>1</b> .
	Robert B.; MARCUS, Stanley A.; of OCHEM NORTH AMERICA, INC.	f	(215) 587-7000  Fascimile No.
	Parkway	•	
	elphia, Pennsylvania 19102-1303 States of America		(215) 587-7075 Teleprinter No.
11000	Deaces of America		
Ma ind	rk this check-box where no agent or common repressicate a special address to which correspondence sho	entative is/has been appould be sent.	ointed and the space above is used instead to
x No.V	DESIGNATION OF STATES		•
e follow	ing designations are hereby made under Rule 4.9(a)	(mark the applicable check	k-boxes; at least one must be marked):
gional P			
X EP	European Patent: AT Austria, BE Belgium, CH : ES Spain, FR France, GB United Kingdom, GR SE Sweden, and any other State which is a Contra	Greece, IT Italy, LU Lo	uxembourg, MC Monaco, NL Netherlands.
OA	OAPI Patent: Benin, Burkina Faso, Cameroon, Ce Mali, Mauritania, Senegal, Togo, and any other St PCT (if other kind of protection or treatment desired, spe	ate which is a member \$	State of OAPI and a Contracting State of the
tional F	Patent (if other kind of protection or treatment desired, spe	cify on dotted line):	
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X KR	Republic of Korea		
X KR	Sri Lanka  Luxembourg		

before the expiration of 15 months from the priority date is to be regarded as withdrawn by the applicant at the expiration of that time limit. (Confirmation of a designation consists of the filing of a notice specifying that designation and the payment of the designation and confirmation fees. Confirmation must reach the receiving Office within the 15-month time limit.)

#### Supplemental Box

If the Supplemental Box is not used, this sheet need not be included in the request.

Use this box in the following cases:

1. If, in any of the Boxes, the space is insufficient to furnish all the information:

in particular:

- (i) if more than three persons are involved as applicants and/or inventors and no "continuation sheet" is available:
- (ii) if, in Box No. II or in any of the sub-boxes of Box No. III, the indication "the States indicated in the Supplemental Box" is checked:
- (iii) if, in Box No. II or in any of the sub-boxes of Box No. III, the inventor or the inventor/applicant is not inventor for the purposes of all designated States or for the purposes of the United States of America:
- (iv) if, in addition to the agent(s) indicated in Box No. IV, there are further agents:
- (v) if, in Box No. V, the name of any State (or OAPI) is accompanied by the indication "patent of addition," "certificate of addition," or "inventor's certificate of addition," or if, in Box No. V, the name of the United States of America is accompanied by an indication "Continuation" or "Continuation-in-part":
- (vi) if there are more than three earlier applications whose priority is claimed:
- 2. If the applicant claims, in respect of any designated Office, the benefits of provisions of the national law concerning non-prejudicial disclosures or exceptions to lack of novelty:

in such case, write "Continuation of Box No. ..." [indicate the number of the Box] and furnish the information in the same manner as required according to the captions of the Box in which the space was insufficient;

in such case, write "Continuation of Box No. III" and indicate for each additional person the same type of information as required in Box No. III;

in such case, write "Continuation of Box No. II" or "Continuation of Box No. III" or "Continuation of Boxes No. II and No. III" (as the case may be), indicate the name of the applicant(s) involved and, next to (each) such name, the State or States (and/or, where applicable, European or OAPI patent) for the purposes of which the named person is applicant;

in such case, write "Continuation of Box No. II" or "Continuation of Box No. III" or "Continuation of Boxes No. II and No. III" (as the case may be), indicate the name of the inventor(s) and, next to (each) such name, the State or States (and/or, where applicable, European or OAPI patent) for the purposes of which the named person is inventor;

in such case, write "Continuation of Box No. IV" and indicate for each further agent the same type of information as required in Box No. IV;

in such case, write "Continuation of Box No. V" and the name of each State involved (or OAPI), and after the name of each such State (or OAPI), the number of the parent title or parent application and the date of grant of the parent title or filing of the parent application;

in such case, write "Continuation of Box No. VI" and indicate for each additional earlier application the same type of information as required in Box No. VI.

in such case, write "Statement Concerning Non-Prejudicial Disclosures or Exceptions to Lack of Novelty" and furnish that statement below.

United States of America [ Application No.] 07/814,366
Filed 26 December 1991 (26.12.91)

United States of America Application No. 07/814,352
(filed 27 December 1991 (27.12.91)

Box No. VI PRIORITY CLAIM Further priority claims are indicated in the Supplemental Box					
The priority of the following e	arlier application				o appreniental Box
Country (in which, or for which, the application was filed)	Fili	ng Date nonthlycar)	Applicat	ion No.	Office of filing (only for regional or international application)
US		ember 1991 .12.91)	07/814,	366	
(2) US	\	ember 1991 .12.91)	07/814,	352	
(3)					
Mark the following check-box if the capplication is the receiving Office (a)  The receiving Office is have a certified copy of the copy of the copy of the cappaign of the copy of the cappaign of the cappaig	certified copy of the fee may be required tereby requested of the earlier ap	e carlier application is to d): I to transmit to the In plication(s) identified	be issued by the Offi ternational labove at item(s)	ce which for the pu	rposes of the present international
Box No. VII EARLIER SE.					
Fill in where a scarch (international, Authority is now requested to base the reference to the relevant application (Country (or regional Office):  US  US  Box No. VIII CHECK LIST	26 December 27 Dec	or other) by the Internation, to the extent possible, thereof) or by reference to Date (day/month/year): ber 1991 (26. ber 1991 (27.	12.91)	Number: 07/8	en carried out or requested and the tify such scarch or request either by 14,366
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(Robert B. HENN)  (Stanley A. MARCUS,	Han				ions from reading the requests.
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1. Date of actual receipt of the international application:		For receiving Of 11 Rec'd PC	7,77. 21[	DEC 1992	2. Drawings:
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4. Date of timely receipt of the corrections under PCT Artic	<u> </u>				not received:
5. International Searching Authorities specified by the applicant:	iority ISA/	6.	Transmittal o until search for	f search copy de ee is paid	layed
Date of receipt of the record co by the International Bureau:	ру	For International B	•		

Form PCT/RO/101 (last sheet) (July 1992)

See Notes to the request form

This sheet is not part of and does not count as a sheet of the international application.

	For receiving Office use only
FEE CALCULATION SHEET	
Annex to the Request	International appreation International Appreach International Inte
Applicant's or agent's file reference IR-3224C+PCT	Date stamp of the receiving Office
Applicant	
ELF ATOCHEM NORTH AMERICA, INC.	
CALCULATION OF PRESCRIBED FEES	
1. TRANSMITTAL FEE	200 T 200
2. SEARCH FEE	410 S 4/0
International search to be carried out by <u>USPTO</u> (If two or more International Searching Authorities are competent in relational application, indicate the name of the Authority which is chosen to carry out the	
3. INTERNATIONAL FEE	
Basic Fee	
The international application contains 19 sheets.	
first 30 sheets	593 b <sub>1</sub> 593
remaining sheets additional amount =	b <sub>2</sub>
Add amounts entered at b and b and enter total at B	593 B
Designation Fee	
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(If that total exceeds the figure which corresponds to the amount of the designation fee multiplied by ten, enter the latter figure in box D.)	
Add amounts entered at B and D and enter total at I	2033 1 2033
4. FEE FOR PRIORITY DOCUMENT	24 P 24
5. TOTAL FEES PAYABLE	
Add amounts entered at T, S, I and P, and enter total in the TOTAL box	2667 2667 TOTAL
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The designation fee is not paid at this time.	
MODE OF PAYMENT	
x authorization to charge deposit account (see below) bank draft	coupons
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DEPOSIT ACCOUNT AUTHORIZATION	
The RO/ US	indicated above to my deposit account.
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is hereby authorized to charge the fee for prep Bureau of WIPO to my deposit account.	paration and transmittal of the priority document to the International
01-2717 <u>December 18, 1992</u>	16 Sel B Lann
Deposit Account Number Date (day/month/year)	Signature Robert B. Henn

#### PCT

## WORLD INTELLECTUAL PROPERTY ORGANIZATION International Bureau



#### INTERNATIONAL APPLICATION PUBLISHED UNDER THE PATENT COOPERATION TREATY (PCT)

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G01G 19/02, C07F 7/22

**A1** 

(11) International Publication Number:

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142

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8 July 1993 (08.07.93)

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(30) Priority data:

07/814,366 07/814,352 26 December 1991 (26.12.91) US 27 December 1991 (27.12.91) US

(60) Parent Applications or Grants

(63) Related by Continuation

US Filed on

Filed on

US

07/814,366 (CIP) 26 December 1991 (26.12.91)

07/814,352 (CIP) 27 December 1991 (27.12.91)

(71) Applicant (for all designated States except US): ELF ATO-CHEM NORTH AMERICA, INC. [US/US]; Three Parkway, Philadelphia, PA 19102-1303 (US). (72) Inventors; and

(75) Inventors/Applicants (for US only): RUSSO, David, A. [US/US]; 22 Brenda Lane, Norristown, PA 19403-2002 (US). DIRKX, Ryan, R. [US/US]; 2006 Turnberry Circle, Glenmoore, PA 19343 (US). FLORCZAK, Glenn, P. [US/US]; 2 Hilltop Boulevard, East Brunswick, NJ 08816-2831 (US).

(74) Agents: HENN, Robert, B. et al.; Elf Atochem North America, Inc., Three Parkway, Philadelphia, PA 19102-1303 (US).

(81) Designated States: AU, BR, CA, CS, HU, JP, KR, NO, NZ, PL, RU, US, European patent (AT, BE, CH, DE, DK, ES, FR, GB, GR, IE, IT, LU, MC, NL, PT, SE).

**Published** 

With international search report.

(54) Title: COATING COMPOSITION FOR GLASS

#### (57) Abstract

A composition for coating glass by chemical-vapor deposition comprises a mixture of a tin oxide precursor monobutyltin trichloride, a silicon dioxide precursor tetraethylorthosilicate, and an accelerant such as triethyl phosphite; the composition is gaseous below 200 °C, and permits coating glass having a temperature from 450 to 650 °C at deposition rates higher than 350 Å/sec. The layer of material deposited can be combined with other layers to produce an article with specific properties such as controlled emissivity, refractive index, abrasion resistance, or appearance.

# 17 Rec'd PCT/PTO 2 1 DEC 1992

## COATING COMPOSITION FOR GLASS

## BACKGROUND OF THE INVENTION

Cross-Reference to Related Application. This application is a continuation-in-part of our copending United States Patent Applications, Serial Numbers 07/814,366, filed 12/26/91 and 07/814,352, filed 12/27/91.

Field of the Invention. The present invention is in the field of coatings on substrates. More particularly, this invention is in the field of compositions for the deposition of coatings at high rates on glass or glass articles to provide controlled refractive index, improved emissivity characteristics, and/or appearance and abrasion resistance, and to complement or enhance other properties.

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Description of the Prior Art. Transparent semi-conductor films such as indium oxide, cadmium stannate, or doped tin oxide, can be applied to various transparent substrates such as, e.g., soda-lime glasses, in order to reflect long-wavelength infrared radiation. Transparent dielectric films such as titanium dioxide or undoped tin oxide can be applied to transparent articles such as glass bottles to form a base coat for a second coating with a specific function. Depending on the thickness of the semiconductor or dielectric film, various reflected iridescent colors may be observed. This iridescent effect is considered to be detrimental to the appearence of the glass in applications such as windows with low emissivity, or bottles for food or beverages.

Methods and apparatus for coating glass, and especially continuous coating on moving glass, are known in the art. A description of apparatus useful in preparing a coated-glass article is found in Lindner, U.S. 4,928,627, made a part of this disclosure by reference herein.

Various procedures have been devised for reducing or eliminating iridescence. For the low-emissivity application, Zaromb, in US 3,378,396, describes an article comprising a transparent glass substrate roated with tin and silicon oxides; the coating varies gradually in composition from a high ratio of silicon oxide to tin oxide at the substrate surface, gradually changing to almost pure tin oxide, and changing further to a ratio of not more than

60% silicon oxide to not less than 40% tin oxide at the interface of that coating with the atmosphere. The refractive index of the coating nearest to the substrate is about 1.5, substantially the refractive index of silica glass, and changes to about 2.0, the refractive index of tin oxide, at the air interface, providing an intermediate coating layer without an optical interface. The article so coated has little to no iridescence in reflected light. Zaromb teaches that aqueous solutions of tin and silicon chlorides can be sprayapplied to achieve his coatings. Spray applications are usually batch operations which do not yield high-quality, uniform films; there is no mention of other means of application such as chemical-vapor deposition (CVD). He also fails to give any indication of the deposition rate, a key parameter for a commercial industrial application.

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Another approach is described by Gordon in US 4,187,336. One or more layers of a transparent material with a refractive index intermediate between that of a glass substrate and a conductive tin oxide film are deposited by atmospheric-pressure CVD between the glass and the tin oxide film. It is necessary for the intermediate layers to have specific refractive indices and thicknesses in order to be effective. It is noted that when the intermediate films contained silicon dioxide, suitable volatile compounds were found to be silane, dimethysilane, diethylsilane, tetramethyl silane, and the silicon halides. No other precursors are mentioned. The deposition rates obtained for the processes described were on the order of from 10 to 20 Ångstroms per second (Å/sec.). Such rates are an order of magnitude below those necessary for a commercial industrial process.

In United States Patent 4,206,252, Gordon describes a process for depositing mixed oxide and nitride coating layers of continuously varying refractive index between a glass substrate and an infra-red-reflecting coating, whereby the film iridesence is eliminated. When silicon dioxide is part of the mixed oxide film, the patent teaches that volatile silicon compounds with Si-Si and Si-H bonds are suitable precursors. Compounds such as 1,1,2,2-tetramethyldisilane, 1,1,2-trimethyldisilane, and 1,2-dimethyldisilane are

disclosed. All of the compounds containing Si-Si and Si-H bonds to which reference is made are expensive, and none are comercially available.

In U.S. 4,386,117, Gordon describes a process for preparing mixed silicon oxide/tin oxide coatings at specific refractive indices or a continuous gradient as taught by Zaromb in US 3,378,396, at optimum deposition rates of 80 to 125 Å/sec, using alkoxy-peralkylpolysilane precursors such as methoxypentamethyldisilane or dimethoxytetramethyldisilane. Again, the silica precursors cited and inferred are impractical for industrial use, because none of them is commercially available on a large scale.

Lagendijk, in United States Patent 5,028,566, notes in column 4 that tetraethyl orthosilicate (TEOS) suffers from a number of disadvantages in its application to a substrate by low-pressure CVD; that is, a pressure of about 500 milliTorr. These disadvantages include difficulty of doping the resultant film with phosphorus, and controlled-source delivery due to the low vapor pressure of TEOS. Lagendijk also points out that attempts at an all-liquid process to produce borophosphosilicate glass have met with limited success. He further equates the dopant effect within a broad range of phosphorus, boron, antimony, arsenic and chromium compounds, but only when used with silicon compounds having no carbon-oxygen-silicon bonds, and two or more silicon atoms.

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In bottle applications, the coatings are applied at such low thicknesses, i.e., about 100 Å, that no iridescence is possible. However, the films are not continuous, and this discontinuity makes them unsuitable for other applications. One solution to the discontinuity is to deposit thicker films of a material with a refractive index closer to that of the article. A mixed metal oxide/silicon oxide material deposited at a significantly more rapid rate than has heretofore been achieved would be desirable, as discussed further hereinbelow.

All the silanes disclosed in the prior art for making mixed metal oxide/
silicon dioxide coatings have certain features which make them unsatisfactory
for commercial development. Some are very corrosive, flammable, or oxygensensitive, and require special handling. Others are not readily available, or

are too expensive for commercial use. Of the materials which can be used, the biggest problem which limits their commercial development in mixed metal oxide/silicon oxide and/or oxynitride intermediate layers has been that of inadequate deposition rates. When the substrate is flat glass and the deposition process is CVD at ambient pressure, the deposition rate of the intermediate layers must be high enough to coat a production-line glass ribbon traveling at line speeds as high as about 15 meters per minute (m/min). Rates for deposition of the desired layers of about 350Å are desirable, and rates on the order of 400 to 600 Å/sec are preferable. Such rates have not heretofore been achieved under conditions which permit continuous, mass production of glass with properties.

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To overcome the problems as discussed hereinabove, silica precursors are needed which are inexpensive, readily available, easy to handle, and have adequate deposition rates when vaporized with metal oxide precursors. Alkoxysilanes such as TEOS, a commodity chemical, would be desirable. 15 However, prior to the present invention, it has not been possible to deposit silicon oxide films from TEOS by atmospheric-pressure CVD at commercially acceptable deposition rates, except at temperatures at or above 700 degrees Celsius (°C). Some success has been achieved at temperatures of from about 450 to about 680°C, but only by modifying the atmospheric-pressure CVD 20 process through plasma enhancement or reduced pressure, neither of which is generally acceptable for commerical use on a continuous glass ribbon. Additives such as oxygen, ozone, or trimethyl phosphite have also been used in these modified processes, but the rates achieved are still lower than those needed for an effective commercial system. 25

D. S. Williams and E. A. Dein, in *J. Electrochem. Soc. 134(3) 657-64* (1987), showed that phosphosilicate and borophosphosilicate glass films with controllable refractive index can be deposited at rates of about 200 Å/sec between 515 and 680°C by the low-pressure CVD of TEOS with phosphorous or boron oxides in concentrations which varied as a function of the additive used. The low-pressure process described here is not amenable to a continuous on-line application of oxides.

In Proceedings, 2nd International ULSI Science and Technical Symposium, ECS Proceedings Vol. 98(9), 571-78 (1989), D. A. Webb et al. reported that silicon oxide films could be deposited from TEOS at rates of about 125 Å/sec in a plasma-enhanced CVD process using oxygen. However, plasma-enhanced CVD is not a viable option for the continuous commmercial application of oxide films to glass, being a batch process requiring complex and costly low-pressure apparatus.

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A. K. Hochberg and D. L. O'Meara in J. Electrochem. Soc. 136(6) 1843 (1989) reported enhanced deposition of silicon oxide films at 570°C by CVD at low pressure when trimethylphosphite was added to TEOS. As with plasma-enhanced CVD, however, low-pressure CVD is not readily utilized for the continuous commercial application of silicon-oxide films on a moving glass sheet to produce a coated-glass article, due at least in part to the cost and complexity of the device used for deposition at low pressure.

From a review of the prior art, it cannot be determined what precursor combinations, if any, can be used for continuous deposition, under conditions and at a rate suitable for mass production, of mixed metal oxide/silicon oxide films at adequate rates from readily available and relatively inexpensive reagents.

Primary or secondary coatings on glass substrates are further useful to enhance or complement properties of either the substrate or one or more of the coatings thereon, improvement of iridesence being only one application. Other uses of coatings include, e.g., protection of the substrate surface from abrasion, addition of color to clear glass, and screening of particular wavelengths of incident radiation.

### DISCUSSION OF THE INVENTION

This invention is a gaseous composition for producing an improved coating on glass, wherein the coated glass exhibits specific properties such as, e.g., controlled refractive index, abrasion resistance, color enhancement, low emissivity, selective light filtration, and anti-iridescence on flat-glass substrates. The invention is made by CVD at rates greater than about 350Å/sec. at atmospheric pressure and at temperatures lower than 700°C, by using a

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mixture which includes at least one precursor for a metal oxide, selected from the group consisting of volatile compounds of tin, germanium, titanium, aluminum, zirconium, zinc, indium, cadmium, hafnium, tungsten, vanadium, chromium, molybdenum, iridium, nickel and tantalum. The gaseous composition further includes a precursor for silicon dioxide, and one or more additives selected from the group consisting of phosphites, borates, water, alkyl phosphine, arsine and borane derivatives; PH<sub>3</sub>, AsH<sub>3</sub> and B<sub>2</sub>H<sub>6</sub>; and O<sub>2</sub>, N<sub>2</sub>O, NF<sub>3</sub>, NO<sub>2</sub> and CO<sub>2</sub>. The additives are termed "accelerants" herein; the accelerants serve to increase the rate of deposition of the film onto the glass from the mixture. The mixture of precursors and additives is gaseous under the conditions of application required to produce the coated-glass article; the reaction of the materials in the gaseous mixture with atmospheric or added oxygen provides the corresponding oxides which are deposited on the glass substrate.

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Those skilled in the art will understand that precursors and materials discussed in this specification must be sufficiently volatile, alone or with other materials, and sufficiently stable under the conditions of deposition, to be a part of the composition from which the desired films are deposited.

Precursors for deposition of metal oxides include, e.g., aluminum alkyls and alkoxides, cadmium alkyls, germanium halides and alkoxides, indium alkyls, titanium halides, zinc alkyls, and zirconium alkoxides. Specific examples of such compounds include, e.g.,  $Al(C_2H_5)_3$ ,  $CrO_2Cl_2$ ,  $GeBr_4$ ,  $Ti(OC_3H_7)_4$ ,  $TiCl_4$ ,  $TiBr_4$ ,  $Ti(C_5H_7O_2)_4$ ,  $Zr(OC_5H_9)_4$ ,  $Ni(CO)_4$ ,  $VCl_4$ ,  $Zn(CH_3)_2$ ,  $Zr(C_5H_9O)_4$ , and the like.

Tin precursors include those described by the general formula R<sub>n</sub>SnX<sub>4-n</sub>, where R is independently chosen from straight, cyclic, or branched-chain alkyl or alkenyl of from one to about six carbons; phenyl, substituted phenyl, or R'CH<sub>2</sub>CH<sub>2</sub>-, where R' is MeO<sub>2</sub>C-, EtO<sub>2</sub>C-, CH<sub>3</sub>CO-, or HO<sub>2</sub>C-; X is selected from the group consisting of halogen, acetate, perfluoroacetate, and their mixtures; and where n is 0, 1, or 2. Preferred precursors for tin oxide in the article of this invention are the organotin halides.

Precursors for silicon oxide include those described by the general formula  $R_mO_nSi_p$ , where m is from 3 to 8, n is from 1 to 4, p is from 1 to 4, and R is independently chosen from hydrogen and acyl, straight, cyclic, or branched-chain alkyl and substituted alkyl or alkenyl of from one to about six carbons, and phenyl or substituted phenyl. Preferred precursors for silicon oxide include tetraethylorthosilicate, diacetoxydi-t-butoxysilane, ethyltriacetoxysilane, methyltriacetoxysilane, methyldiacetoxylsilane, tetramethyldisiloxane, tetramethylcyclotetrasiloxane, dipinacoloxysilane, 1,1-dimethylsila-2-oxacyclohexane, tetrakis (1-methoxy-2-propoxy) silane, and triethoxysilane.

Suitable accelerants include phosphite and borate derivatives of the general formula (R<sup>n</sup>O)<sub>3</sub>P and (R<sup>n</sup>O)<sub>3</sub>B, where R<sup>n</sup> is independently chosen from straight, cyclic, or branched-chain alkyl or alkenyl of from one to about six carbons; phenyl, substituted phenyl, or R<sup>n</sup>CH<sub>2</sub>CH<sub>2</sub>, where R<sup>n</sup> is MeO<sub>2</sub>C, EtO<sub>2</sub>C-, CH<sub>3</sub>CO-, or HO<sub>2</sub>C-; R<sup>n</sup> is preferably alkyl or alkenyl of from 1 to 4 carbons in length. Particularly preferred accelerants are those selected from the group consisting of boron and phosphorus esters; most preferred are TEB and TEP.

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The precursors to the overcoated layer comprise MBTC or any of the organotins described by the general formula  $R_n SnX_{4-n}$  above, and a material chosen to impart a semi-conductive property to the tin oxide; such materials include, e.g., antimony compounds such as trimethylantimony, phosphorous compounds such as triethylphosphine, and fluorine-containing compounds such as trifluoroacetic acid, trifluoroacetic anhydride, ethyl trifluoroacetate, 2,2,2-trifluoroacetic acid, trifluoroacetoacetone, heptafluorobutyryl chloride, and hydrogen fluoride. The tin oxide layer can also be made conductive by depositing sub-stoichiometric films having the composition  $SnO_{2-r}$ , wherein x is a non-integer having a value between zero and 1, and wherein the value of x can vary within a given film. The materials for imparting semi-conductive properties to the tin oxide can also be added to the precursors for the first layer, to enhance the emissivity of the entire coating system, i.e., the emissivity of the combined first and second layers.

Those skilled in the art will realize that the tin oxide can be replaced in these films entirely or in part by the oxides of other metals such as, e.g., germanium, titanium, aluminum, zirconium, zinc, indium, cadmium, hafnium, tungsten, vanadium, chromium, molybdenum, iridium, nickel and tantalum.

# DESCRIPTION OF THE PREFERRED EMBODIMENTS

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The preferred embodiment of the present invention is a gaseous composition at a temperature below about 200°C at atmospheric pressure, adapted to deposit a film of tin oxide and silicon oxide at a rate greater than about 350Å/sec. which comprises a precursor of tin oxide, a precursor of silicon oxide, an accelerant selected from the group consisting of organic phosphites, organic borates and water, and mixtures thereof, and a source of oxygen.

In another embodiment of this invention, the composition results in a film deposited at atmospheric pressure wherein the film comprises one or more mixed metal oxide/silicon dioxide films on a glass substrate, the deposition being made from a mixture comprising a metal oxide precursor, a silicon dioxide precursor, and at least one additive which improves or accelerates the deposition rate significantly when compared to the deposition rate without the additive. The deposited films can contain additional oxides related to the additives used. Further, the deposited mixed oxide films can have specific properties in their own right such as, e.g., designed refractive index, or can be combined with other films, under- or overcoated, or both, to have a combined property such as, e.g., color neutrality or lubricity.

In a more-preferred embodiment, the composition provides a mixed metal oxide/silicon dioxide film comprising multiple tin oxide/silicon dioxide layers of, e.g., increasing refractive index; further, a chosen property of a given layer, such as, e.g., the refractive index, can vary continuously such that an overcoated layer of tin oxide will have minimal reflected color. A given layer may thus have a concentration of silicon oxide and tin oxide different from the concentrations of silicon oxide and tin oxide in an adjacent layer. The films can also contain oxides of the accelerants, particularly when the additives contain phosphorus or boron.

In a most-preferred embodiment of the composition of this invention, the precursors to the mixed oxide layer comprise organotin halides generally and monobutyltin trichloride (MBTC) in particular, TEOS, and the accelerant triethyl phosphite (TEP).

The compositions of the films produced by this invention were determined by X-ray diffraction (XRD) and X-ray photoelectron spectroscopy (XPS). The article of the present invention is prepared by a process using accelerants whereby the process provides a commercially acceptable continuous CVD deposition of oxide films on moving glass, especially on a modern float-glass line, where the batch processes of the prior art are entirely inapplicable.

The effects of added water and added phosphites and borates on the refractive index and deposition rate of TEOS-based mixed oxide films are shown in the following Tables. These results are contrasted to those in Tables IV and V, which show the effect of the additives oxygen and a Lewis acid.

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Table I shows the effect of added water. As the water concentration is increased, regardless of the tin/silicon ratio or the gas velocity, the deposition rate increases to commercially significant levels. These rate increases are also accompanied by increases in refractive index. In the tables here, the reported deposition rates are approximate with a range of about seven percent, unless the rate is followed by an expressed  $\pm$  uncertainty.

TABLE I

Effect of Water Concentration on Mixed Oxide
Refractive Index and Deposition Rate

5		MBTC mol%	TEOS mol%	Water mol%	R.I.	Dep. Rate _A/sec
	665°C glass	temperature,	160°C systein	temperature,	50 l/min gas	flow.
10		0.71 0.71 0.71	0.71 0.71 0.71	0.00 0.15 0.24	1.54 1.73 1.74	25 340 400
15	665°C glass	temperature,	160°C system	temperature,	12.5 l/min gas	s flow.
		1.05 1.05 1.05	0.59 0.59 0.59	0.00 0.60 1.10	1.74 1.78 1.80	290 330 480

While 160°C is preferred, the system temperature can be from about 125 to about 200°C.

Table II shows the effects of added TEP and of mixtures of TEP and lower-alkyl borate esters such as triethyl borate (TEB). The results show that TEP is very effective in accelerating the deposition rates of the mixed-oxide films to a high rate at specific and controlled refractive-index values. Additions of TEB at low levels to the TEP resulted in an additional small increase in rate. As used in this specification, the term "high rate," as applied to the film deposition described herein, is greater than about 350Å/sec, and preferably about 400Å/sec or higher. All the films produced under the conditions of Table II were clear.

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TABLE II

Effect of MBTC/TEOS/TEP Concentrations on Deposition Rate

5	%TEOS	%MBTC	%TEP	%TEB	R.I.	Dep. Rate
	0.80	0.16	-	•	$1.69 \pm .02$	38± 3
	0.80	0.11	0.76	•	$1.58 \pm .01$	542 ± 8
10	0.80	0.16	0.76	•	$1.60\pm.01$	416±22
	0.78	1.56	0.75	-	$1.67 \pm .01$	505 ± 4
	0.78	1.84	0.75	•	$1.69 \pm .01$	$476 \pm 45$
	0.28	1.56	0.36		$1.73 \pm .01$	231±46
15	0.27	1.56	0.62	•	$1.71 \pm .01$	$381 \pm 15$
	0.27	1.56	0.75	•	$1.70\pm.01$	482± 6
	0.27	1.56	0.75	•	$1.70 \pm .01$	482 ± 16
	0.27	1.56	0.74	0.18	$1.70 \pm .02$	492±13
20	0.79	0.16	0.76	0.19	$1.59 \pm .01$	$473 \pm 56$

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The glass temperature was 665°C, its speed, 0.56 m/sec; system temperature 160°C, air. MBTC, TEOS, and TEP or the mixture of TEP and TEB were injected separately into the vaporizer section of the coater. Each data point was the average of three samples. The dew point was from -74 to -78°C.

Table III shows the effect of added oxygen. Increasing the oxygen concentration increases the deposition rate significantly, but not to the levels needed for commercial application.

TABLE III

Effect of Oxygen Concentration On Mixed Oxide
Refractive Index and Deposition Rate

35	MBTC mol%	TEOS mol%	Oxygen vol% of air	R.I.	Dep. Rate A/sec
	0.71	0.71	20	1.54	25
	0.71	0.71	50	1.63	50
40	0.71	0.71	75	1.65	160
	0.71	0.71	100	1.66	240

665°C glass temperature, 160°C system temperature, 50 l/min gas flow.

Table IV shows the effect of added Lewis acid, which in this case is excess MBTC. As the concentration increases, the rate increases, although not to the levels needed for commercial application.

#### Table IV

Etiect of MBTC Concentration on Mixed Oxide Refractive Index and Deposition Rate

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10	MBTC mol%	TEOS mol%	R.I.	Dep. Rate <u>A/sec</u>
	0.48 0.48 + 0.23 0.48	1.78 1.78	160	
	0.48 + 0.47	0.47	1.85	200 300

665°C glass temperature, 160°C system temperature, 50 l/min gas flow. 15

The data in the tables show that effective CVD of mixed oxide films can be achieved at commercial rates by the present invention, with concomitant control of refractive index. The following examples illustrate preferred embodiments of this invention.

### Example 1

A square plate of soda-lime silica glass, 9 centimeters (cm.) on a side, was heated on a hot block to 665°C. A gas mixture of about 0.16 mol% MBTC, 0.80 mol% TEOS, 0.75 mol% TEP, and the balance hot air at 160°C was directed over the glass at a rate of 12.5 liters per minute (l/min) for about 10 seconds. The center of the glass surface was uniformly coated with a film which had a pale green color in reflected light. Using the Prism Coupler technique, the refractive index was found to be 1.60 and the thickness was about 4260 Å, corresponding to a deposition rate of about 426 Å/sec. Similarly deposited films have been shown to be amorphous by XRD, and to be composed of oxides of tin, silicon and phosphorus by XPS.

#### Example 2

A gas mixture of about 1.84 mol% MBTC, 0.78 mol% TEOS, 0.75 mol% TEP, and the balance hot air was directed over a glass surface in the same manner as described in Example 1. The resulting film had a pale magenta color in reflected light. The refractive index was found to be 1.68,

and the thickness was about 4930 Å, corresponding to a deposition rate of about 493 Å/sec. Similarly deposited films have been shown to be amorphous by XRD, and to be composed of oxides of tin, silicon and phosphorus by XPS.

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## Example 3

A gas mixture of about 1.22 mol% MBTC, 0.58 mol% TEOS, 1.09 mol% H<sub>2</sub>O and the balance hot air was directed over a glass surface as described in Example 1, but for eight seconds. The resulting film had a green color in reflected light. The refractive index was found to be 1.78, and the film thickness was about 4650 Å, which corresponds to a deposition rate of about 580 Å/sec. From XRD analysis, similarly deposited films have been found to consist of collapsed tetragonal unit cells of tin oxide, indicating some solid-solution formation with silicon dioxide. XPS analysis shows that the films comprise oxides of tin and silicon.

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### Example 4

Each of the films described in Examples 1 through 3 was successively deposited for one second in ascending-index order. The multi-layer film was then overcoated with about 3200 Å of fluorine-doped tin oxide. This film construction provided a transparent article with essentially no reflected color under conditions of daylight illumination.

## Example 5

A 9-cm. square of soda-lime silica glass was heated on a hot block to 665°C. A gas mixture of about 1.04 mol% MBTC in air at 160°C, and a gas mixture of 1.04 mol% TEOS and 0.20 mol% TEP in air at 160°C were directed through two microprocessor-controlled globe valves over the glass at a total flow rate of 12.5 l/min for 30 sec. The globe valves were simultaneously opened and closed at a programmed rate such that the gas composition impinging on the glass sample was continuously changed from a mixture of high TEOS/TEP and low MBTC to a mixture of low TEOS/TEP and high MBTC. The center of the glass surface was uniformly coated with a film consisting of oxides of tin, silicon and phosphorus as determined by XPS analysis. As the film thickness increased, the amount of tin gradually

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increased, while the amount of silicon and phosphorus decreased. The refractive index was calculated from these data, and from data derived from standard films, and found to lie between 1.52 and 1.87. This film construction provided an article with essentially no reflected color when overcoated with fluorine-doped tin oxide.

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### Example 6

A gas mixture of about 0.16 mol% MBTC, 0.80 mol% TEOS, and the balance hot air was directed over a glass surface as described in Example 1 for about 60 seconds. The resulting film had a magenta color in reflected light, and a refractive index of 1.69. The film thickness was about 2260 Å, corresponding to a deposition rate of about 38 Å/sec.

## Example 7

A 0.5-1 clear-glass beverage bottle was rotated and heated to about 600°C in an oven over a three-minute period. The heated bottle was transferred into a coating chamber, where it was contacted with a vapor mixture of 0.16 mol% MBTC, 0.80 mol% TEOS, 0.75 mol% TEP, and the balance hot air at about 170°C for 10 sec. The resulting film was magentablue in color, and was uniformly distributed on the sidewalls of the container from shoulder to base. The deposition rate was estimated to be about 200 Å/sec from the film color, compared to about 50 Å/sec for the bottle coated only with the vapor mixture of MBTC and TEOS.

From a review of the foregoing tables and examples, those skilled in the art will realize that TEB, TEP, and water serve as accelerants in the CVD of oxide films on glass, and that TEP and TEB are synergistic in accelerating the deposition rate of TEOS and MBTC. Accelerants useful in this invention are chosen from the group consisting of borate and phosphite esters, alkyltin halides, and water.

While the composition of the present invention is preferably applied continuously to a moving glass substrate by methods known to those skilled in the art, the composition of this invention also has utility in batch processes. In application under conditions of continuous deposition, the composition is preferably maintained at temperatures below about 200°C, and more

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preferably below about 175°C, and applied to the glass moving at about 15 meters per second to provide deposition at a rate of at least 350Å/sec., and preferably at a rate of at least 400Å/sec.

Modifications and improvements to the preferred forms of the invention disclosed and described herein may occur to those skilled in the art who come to understand the principles and precepts hereof. Accordingly, the scope of the patent to be issued hereon should not be limited solely to the embodiments of the invention set forth herein, but rather should be limited only by the advance by which the invention has promoted the art.

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### WHAT IS CLAIMED IS:

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- 1. A gaseous composition at a temperature below about 200°C at atmospheric pressure, adapted to deposit at least a first layer of tin oxide and silicon oxide onto glass at a rate of deposition greater than about 350Å/sec. at a temperature below about 200°C, at atmospheric pressure, wherein the composition comprises a precursor of tin oxide, a precursor of silicon oxide, an accelerant selected from the group consisting of organic phosphites, organic borates and water, and mixtures thereof, and a source of oxygen.
- 2. The composition of claim 1 wherein the substrate is transparent flat glass at a temperature of from about 450 to about 650°C.
- 3. The composition of claim 1 producing a glass article having essentially no reflected color in daylight.
- 4. The composition of claim 1 wherein the glass substrate is moving and the deposition is continuous.
  - 5. The composition of claim 1 at a temperature below about 175°C.
- 6. The composition of claim 1 wherein the accelerant is triethyl phosphite.
- 7. The composition of claim 1 wherein the precursor of the tin oxide is  $R_n SnX_{4-n}$ , where R is a straight, cyclic, or branched-chain alkyl, or alkenyl of from one to about six carbons; phenyl, substituted phenyl, or  $R'CH_2CH_2$ , where R' is  $MeO_2C$ -,  $EtO_2C$ -,  $CH_3CO$ -, or  $HO_2C$ -; X is selected from the group consisting of halogen, acetate, perfluoroacetate, and their mixtures; and where n is 0, 1, or 2.
- 8. The composition of claim 1 wherein the precursor of the tin oxide is an alkyltin halide.
- 9. The composition of claim 1 wherein the precursor of the tin oxide is an alkyltin chloride.
- 10. The composition of claim 1 wherein the precursor of the tin oxide is chosen from the group consisting of monobutylytin trichloride, dibutylytin dichloride, tributylytin chloride, and tin tetrachloride.
- 11. The composition of claim 1 wherein the precursor of silicon oxide is  $R_mO_nSi_p$ , where m is from 3 to 8, n is from 1 to 4, p is from 1 to 4, and

R is independently chosen from hydrogen and acyl, straight, cyclic, or branched-chain alkyl and substituted alkyl or alkenyl of from one to about six carbons, and phenyl or substituted phenyl.

- 12. The composition of claim 1 wherein the precursor of silicon oxide is selected from the group consisting of tetraethylorthosilicate, diacetoxydi-t-butoxysilane, ethyltriacetoxysilane, methyltriacetoxysilane, methyldiacetoxylsilane, tetramethyldisiloxane, tetramethylcyclotetrasiloxane, dipinacoloxysilane, 1,1-dimethylsila-2-oxacyclohexane, tetrakis (1-methoxy-2-propoxy) silane, and triethoxysilane.
- 13. The composition of claim 1 wherein the precursor of silicon oxide is tetraethylorthosilicate.
  - 14. The composition of claim 1 wherein the accelerant comprises triethyl phosphite.
- 15. The composition of claim 1 wherein the accelerant comprises triethyl phosphite and triethyl borate.
  - 16. The composition of claim 1 wherein the rate of deposition is greater than about 400Å/sec.
    - 17. The composition of claim 1 wherein the first layer is amorphous.
  - 18. The composition of claim 1 wherein the first layer comprises a plurality of layers, and at least a second layer is deposited on the first layer.
  - 19. The composition of claim 18 wherein the second layer comprises a tin oxide.
  - 20. The composition of claim 18 wherein the second layer comprises a mixture of tin oxide and a fluorine compound.
- 21. The composition of claim 18 wherein the first layer has a refractive index which changes continuously between the substrate and the second layer.
  - 22. The composition of claim 18 wherein the second layer comprises a doped tin oxide.
- 30 23. The composition of claim 18 wherein the second layer is deposited from a precursor mixture comprising monobutyltin trichloride and a fluorine-containing material.

- 24. The composition of claim 18 wherein the first layer is deposited from a precursor mixture comprising monobutyltin trichloride and tetraethyl orthosilicate in the presence of triethyl phosphite.
- 25. A gaseous composition adapted to deposit at least a first layer of tin oxide and silicon oxide onto glass at a temperature below about 200°C, at atmospheric pressure, by the method of depositing at least one amorphous layer onto glass at a rate greater than about 400Å/sec., the layer having a controlled index of refraction, by applying to the glass a mixture of a tin oxide precursor, a silicon oxide precursor, and at least one accelerant chosen from the group consisting of boron and phosphorus esters and water.
- 26. The composition of claim 25 applied by continuous chemical-vapor deposition of a mixture of monobutyltin trichloride, tetraethylorthosilicate and an accelerant onto a moving glass sheet, wherein the glass is at a temperature of from about 450 to about 650°C.

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